

ON Semiconductor®

## FQB34P10TM-F085

### **100V P-Channel MOSFET**

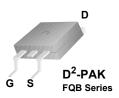
### **General Description**

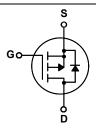
These P-Channel enhancement mode power field effect transistors are produced using ON Semiconductor's proprietary, planar stripe, DMOS technology.

This advanced technology has been especially tailored to minimize on-state resistance, provide superior switching performance, and withstand high energy pulse in the avalanche and commutation mode. These devices are well suited for low voltage applications such as audio amplifier, high efficiency switching DC/DC converters, and DC motor control.

#### **Features**

- -33.5A, -100V,  $R_{DS(on)} = 0.06\Omega @V_{GS} = -10 V$
- Low gate charge ( typical 85 nC)
- Low Crss (typical 170 pF)
- Fast switching
- 100% avalanche tested
- · Improved dv/dt capability
- · 175°C maximum junction temperature rating
- Qualified to AEC Q101
- · RoHS Compliant





### Absolute Maximum Ratings T<sub>C</sub> = 25°C unless otherwise noted

Symbol	Parameter		FQB34P10TM-F085	Units	
V <sub>DSS</sub>	Drain-Source Voltage		-100	V	
I <sub>D</sub>	Drain Current - Continuous (T <sub>C</sub> = 25°C)		-33.5	Α	
	- Continuous (T <sub>C</sub> = 100°C)		-23.5	Α	
I <sub>DM</sub>	Drain Current - Pulsed	(Note 1)	-134	Α	
V <sub>GSS</sub>	Gate-Source Voltage		± 25	V	
E <sub>AS</sub>	Single Pulsed Avalanche Energy	(Note 2)	2200	mJ	
I <sub>AR</sub>	Avalanche Current	(Note 1)	-33.5	Α	
E <sub>AR</sub>	Repetitive Avalanche Energy	(Note 1)	15.5	mJ	
dv/dt	Peak Diode Recovery dv/dt	(Note 3)	-6.0	V/ns	
P <sub>D</sub>	Power Dissipation (T <sub>A</sub> = 25°C) *		3.75	W	
	Power Dissipation (T <sub>C</sub> = 25°C)		155	W	
	- Derate above 25°C		1.03	W/°C	
T <sub>J</sub> , T <sub>STG</sub>	Operating and Storage Temperature Range		-55 to +175	°C	
T <sub>L</sub>	Maximum lead temperature for soldering purposes, 1/8" from case for 5 seconds		300	°C	

### **Thermal Characteristics**

Symbol	Parameter	Тур	Max	Units
$R_{\theta JC}$	Thermal Resistance, Junction-to-Case		0.97	°C/W
$R_{\theta JA}$	Thermal Resistance, Junction-to-Ambient *		40	°C/W
$R_{\theta JA}$	Thermal Resistance, Junction-to-Ambient		62.5	°C/W

<sup>\*</sup> When mounted on the minimum pad size recommended (PCB Mount)

Symbol	Parameter	Test Conditions	Min	Тур	Max	Units
Off Cha	aracteristics					
BV <sub>DSS</sub>	Drain-Source Breakdown Voltage	$V_{GS} = 0 \text{ V}, I_{D} = -250 \mu\text{A}$	-100			V
$\Delta BV_{DSS}$ / $\Delta T_{J}$	Breakdown Voltage Temperature Coefficient	I <sub>D</sub> = -250 μA, Referenced to 25°C		-0.1		V/°C
I <sub>DSS</sub>	Zero Gate Voltage Drain Current	V <sub>DS</sub> = -100 V, V <sub>GS</sub> = 0 V			-1	μΑ
		V <sub>DS</sub> = -80 V, T <sub>C</sub> = 150°C			-10	μΑ
I <sub>GSSF</sub>	Gate-Body Leakage Current, Forward	V <sub>GS</sub> = -25 V, V <sub>DS</sub> = 0 V			-100	nA
I <sub>GSSR</sub>	Gate-Body Leakage Current, Reverse	V <sub>GS</sub> = 25 V, V <sub>DS</sub> = 0 V			100	nA
On Cha	aracteristics					
V <sub>GS(th)</sub>	Gate Threshold Voltage	V <sub>DS</sub> = V <sub>GS</sub> , I <sub>D</sub> = -250 μA	-2.0		-4.0	V
R <sub>DS(on)</sub>	Static Drain-Source On-Resistance	V <sub>GS</sub> = -10 V, I <sub>D</sub> = -16.75 A		0.049	0.06	Ω
9 <sub>FS</sub>	Forward Transconductance	V <sub>DS</sub> = -40 V, I <sub>D</sub> = -16.75 A (Note 4)		23		S
C <sub>iss</sub> C <sub>oss</sub> C <sub>rss</sub>	Output Capacitance Reverse Transfer Capacitance	$V_{DS} = -25 \text{ V}, V_{GS} = 0 \text{ V},$ f = 1.0 MHz		730 170	950 220	pF pF
	-			170	220	p⊦
	ing Characteristics	I				
t <sub>d(on)</sub>	Turn-On Delay Time	$V_{DD} = -50 \text{ V}, I_{D} = -33.5 \text{ A},$		25	60	ns
t <sub>r</sub>	Turn-On Rise Time	$R_G = 25 \Omega$		250	510	ns
t <sub>d(off)</sub>	Turn-Off Delay Time	(Note 4, 5)		160	330	ns
t <sub>f</sub>	Turn-Off Fall Time			210	430	ns
Q <sub>g</sub>	Total Gate Charge	$V_{DS} = -80 \text{ V}, I_{D} = -33.5 \text{ A},$		85	110	nC
Q <sub>gs</sub>	Gate-Source Charge	V <sub>GS</sub> = -10 V		15		nC
Q <sub>gd</sub>	Gate-Drain Charge	(Note 4, 5)		45		nC
Drain-S	Source Diode Characteristics a	nd Maximum Ratings				
I <sub>S</sub>	Maximum Continuous Drain-Source Diode Forward Current				-33.5	Α
	Maximum Pulsed Drain-Source Diode Forward Current				-134	Α
I <sub>SM</sub>						l
	Drain-Source Diode Forward Voltage	$V_{GS} = 0 \text{ V}, I_{S} = -33.5 \text{ A}$			-4.0	V
I <sub>SM</sub> V <sub>SD</sub> t <sub>rr</sub>	Drain-Source Diode Forward Voltage Reverse Recovery Time	$V_{GS} = 0 \text{ V, } I_S = -33.5 \text{ A}$ $V_{GS} = 0 \text{ V, } I_S = -33.5 \text{ A,}$		 160	-4.0 	V

- Notes: 
  1. Repetitive Rating : Pulse width limited by maximum junction temperature 2. L =3.9mH, I<sub>AS</sub> = -33.5A, V<sub>DD</sub> = -25V, R<sub>G</sub> = 25 Ω, Starting T<sub>J</sub> = 25°C 3. I<sub>SD</sub> ≤ -33.5A, di/dt ≤ 300A/μs, V<sub>DD</sub> ≤ BV<sub>DSS</sub>, Starting T<sub>J</sub> = 25°C 4. Pulse Test : Pulse width ≤ 300μs, Duty cycle ≤ 2% 5. Essentially independent of operating temperature

### **Typical Characteristics**

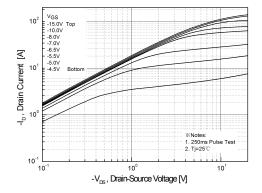


Figure 1. On-Region Characteristics

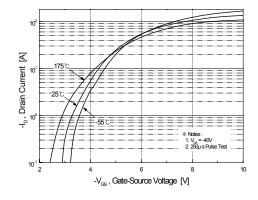


Figure 2. Transfer Characteristics

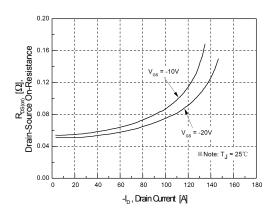


Figure 3. On-Resistance Variation vs. Drain Current and Gate Voltage

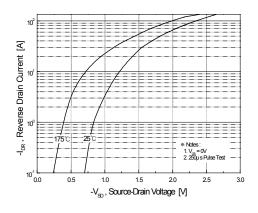


Figure 4. Body Diode Forward Voltage Variation vs. Source Current and Temperature

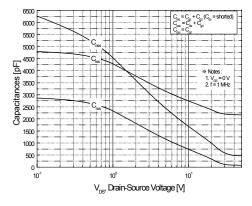


Figure 5. Capacitance Characteristics

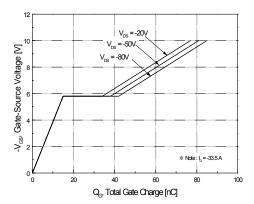


Figure 6. Gate Charge Characteristics

### Typical Characteristics (Continued)

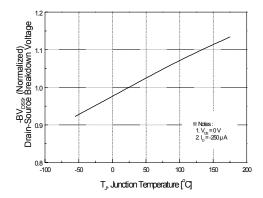


Figure 7. Breakdown Voltage Variation vs. Temperature

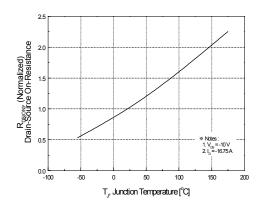


Figure 8. On-Resistance Variation vs. Temperature

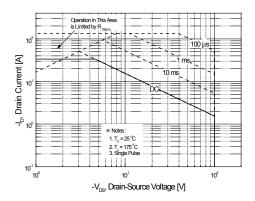


Figure 9. Maximum Safe Operating Area

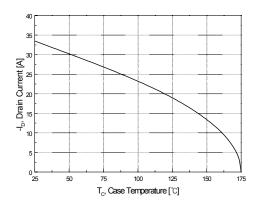


Figure 10. Maximum Drain Current vs. Case Temperature

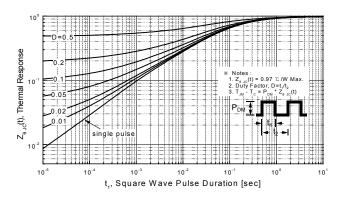
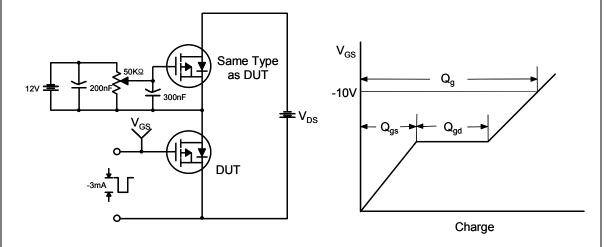
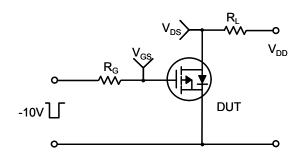


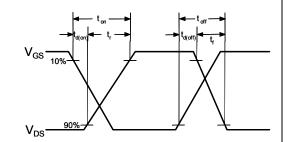
Figure 11. Transient Thermal Response Curve

### **Gate Charge Test Circuit & Waveform**

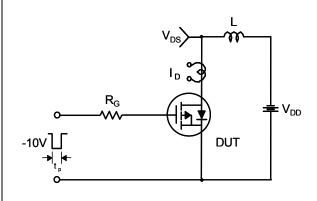


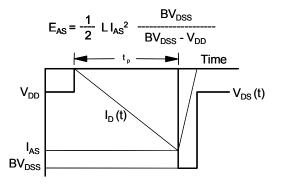
### **Resistive Switching Test Circuit & Waveforms**



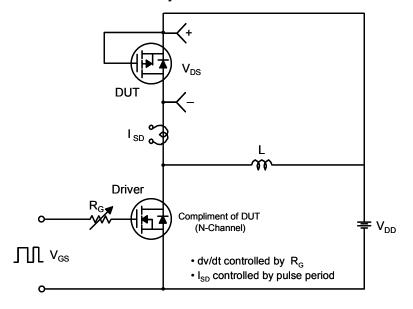


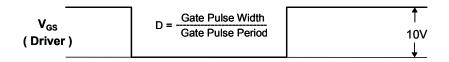
### **Unclamped Inductive Switching Test Circuit & Waveforms**

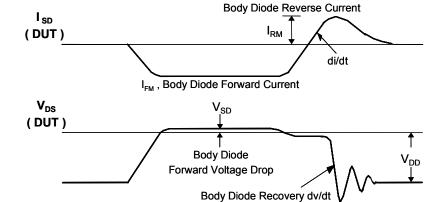




### Peak Diode Recovery dv/dt Test Circuit & Waveforms







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